

## Supporting Information

### **Ultra-flexible organic solar cells based on eco-friendly cellulose substrate with efficiency approaching 19%**

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**Materials:**

All materials were used as obtained unless otherwise indicated. Silver nanowires (AgNWs) (10 wt% in H<sub>2</sub>O with an average length of ~25 μm and diameter of ~35 nm) were purchased from Zhejiang Kechuang Adv. Mater. Co., Ltd. PM6, BO-4Cl, Y6, PBDB-T and ITIC-4F were purchased from Solarmer Materials (Beijing) Inc. L8-BO was purchased from Jiaxing Hyper Inc. Poly (sodium 4-styrenesulfonate) (PSSNa, Mw ~500,000, powder), 1,8-diiodooctane (DIO) were purchased from Sigma-Aldrich. Ethyl cellulose (EC), Ethoxylated trimethylolpropane triacrylate (ETPTA) and 2-Hydroxy-2-methylpropiophenone were purchased from Adamas Reagent Co., Ltd. The indium-doped tin oxide (ITO)-coated glass and PET/ITO, PEN/ITO were purchased from Liaoning Advanced Election Technology. ZnO nanoparticles (NPs) were synthesized according to the literature.<sup>1</sup>

**Electrode Fabrication:**

The EC solution was prepared by dissolving 0.05 g of EC into 1 mL of methanol (Kemiou, 99.8%). After EC solution was filtered, different contents of ETPTA with 2-Hydroxy-2-methylpropiophenone (3wt%, as initiator) were added to obtain EC@ETPTA solution. EC@ETPTA solution were deposited on the glass by spin coating to obtain the EC@ETPTA films (7-8 μm). For preparing EC@ETPTA/AgNWs electrode, the EC@ETPTA substrate was treated by plasma for 8 min and a thin layer (~20 nm) ZnO NPs was deposited on the flexible substrate, then AgNWs was spinning coated following our previous report.<sup>2</sup>

**Electrode characterization.**

Sheet resistances of the glass/ITO, PET/ITO, PEN/ITO and EC@ETPTA/AgNWs were measured with a ST-2258C four-probe instrument (Suzhou Jingge Electronic). Atomic force microscope (AFM) investigation was performed using Bruker MultiMode 8 in tapping mode. AFM-IR experiments were carried out using a commercial AFM-IR setup (Bruker nanoIR 3) that consists of an AFM microscope operating in contact mode and a Quantum Cascade Laser (QCL laser). The surface and cross-section morphologies of EC@ETPTA and EC@ETPTA/AgNWs were measured by SEM (ZEISSMERLIN Compact). The stretch ability was measured by cupping machine (Transcell Technology BAB-10MT). The UV-Vis spectra were obtained by a Cary

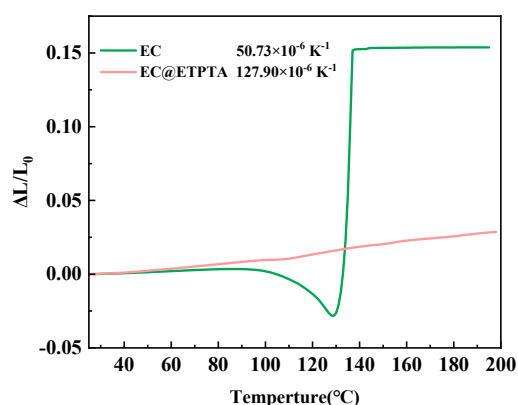
5000 UV-Vis spectrophotometer. The thermal expansion coefficient measurements were performed using a Thermal Mechanical Analysis (TMA) (PE DMA8000). The Stress-strain measurements were performed using a mechanical tester (CTM-2GD) with a pre-strain of 5% in the temperature range of 25°C at an environmental RH of 35%.

### **Device fabrication:**

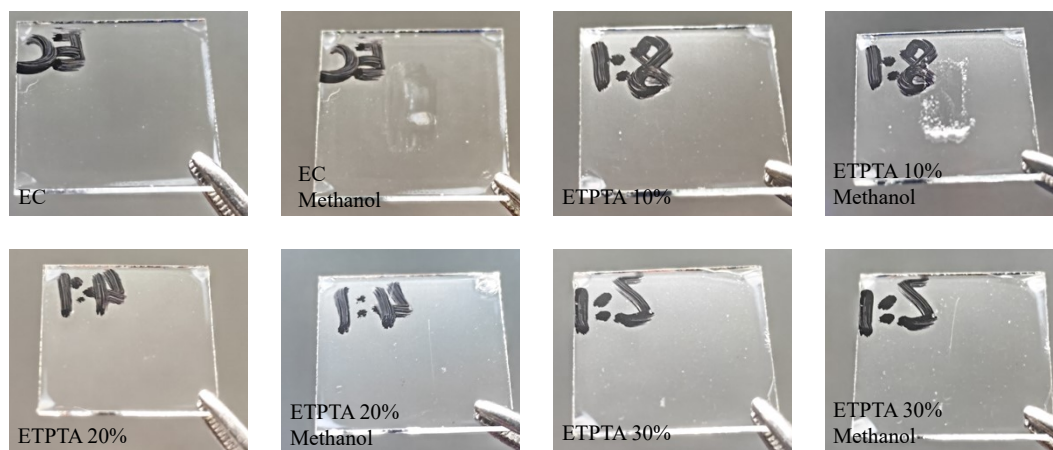
The OSCs devices were fabricated using an inverted structure of Electrode/ZnO /active layers/MoO<sub>x</sub>/Ag. For rigid devices, ITO was ultrasonically cleaned with detergent, deionized water, acetone, isopropanol and UV-treated for 15 min. ZnO nanoparticle (ZnO NPs)<sup>3</sup> layer (~ 20 nm) was deposited by spin coating on top of precleaned ITO substrates and annealed at 120 °C for 10 mins. Different active layers were deposited following procedures in previous reports<sup>4-8</sup>. Then, MoO<sub>x</sub> (~5 nm) and Ag (~100 nm) were successively evaporated onto the active layer through a shadow mask (pressure ca. 10<sup>-4</sup> Pa). The device area is ~4 mm<sup>2</sup>. The flexible devices based on the EC@ETPTA/AgNWs and PET/ITO and PEN/ITO electrodes were fabricated following the same procedure to that of the rigid devices.

### **Device characterization.**

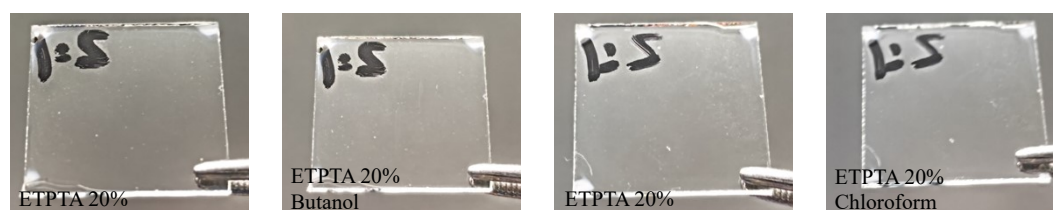
The J-V characteristics of photovoltaic devices were measured using a Keithley 2400 source measure unit, with a fixed scan speed of 0.02 V s<sup>-1</sup> and dwell times of 20 ms for the J-V curves. The photocurrent was measured under illumination simulated 100 mW cm<sup>-2</sup> AM1.5G irradiation using an Enli SS-F5-3A solar simulator, calibrated with a standard Si solar cell (Enli Technology Co., Ltd., Taiwan, and calibrated report can be traced to NREL). The external quantum efficiency (EQE) spectrum was measured using a QE-R Solar Cell Spectral Response Measurement System (Enli Technology Co., Ltd., Taiwan). The thickness of film and device was measured using a Veeco Dektak 150 profilometer.



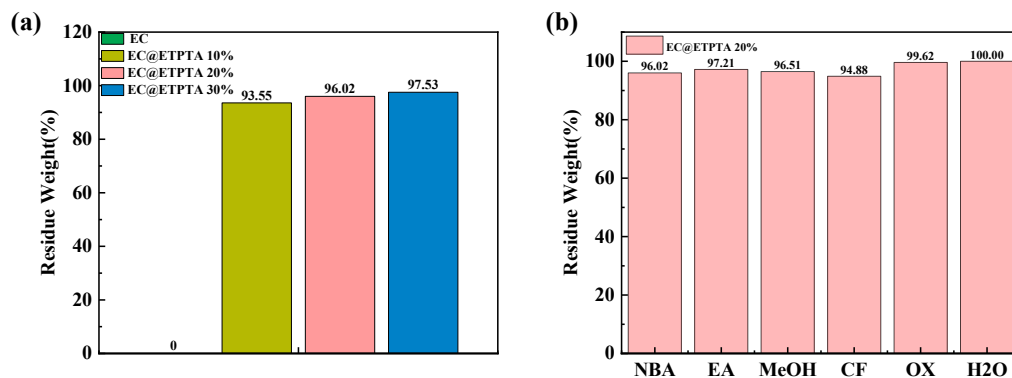
**Fig. S1.** The values of thermal expansion coefficients (TEC) for the EC and EC@ETPTA.



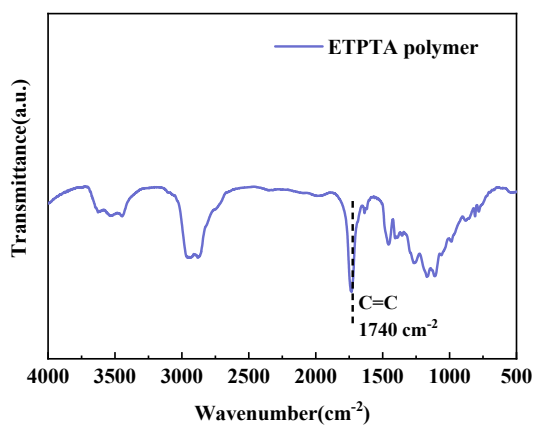
**Fig. S2.** Pure EC and EC@ETPTA films with different ETPTA contents were subjected to solvent resistance testing against methanol following ASTM D5402-19.



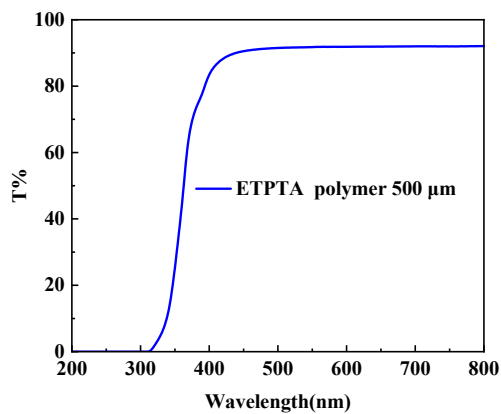
**Fig. S3.** Stability of EC@ETPTA films with 20% ETPTA content were subjected to solvent resistance testing against butanol and chloroform following ASTM D5402-19.



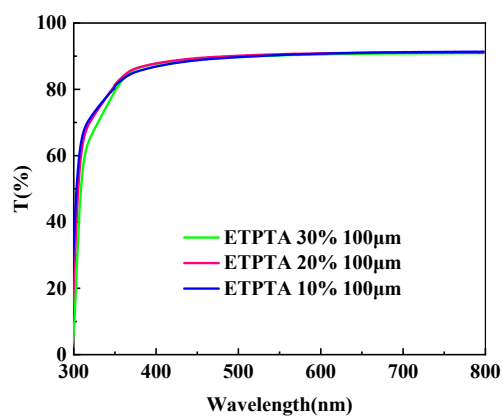
**Fig. S4.** Residue weight of the a) dried EC and EC@ETPTTA containing different ETPTA content films after soaking in n-butanol and b) EC@ETPTTA containing 20% ETPTA after soaking in different solvents for 24 h.



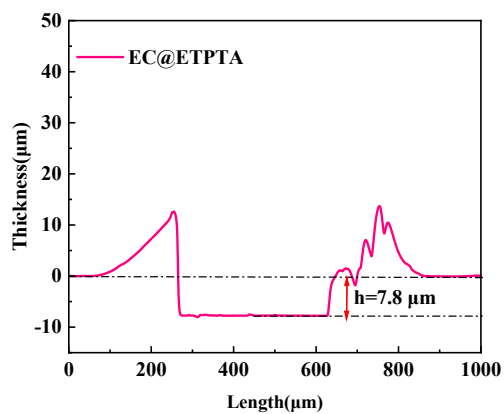
**Fig. S5.** FT-IR spectra of ETPTA polymer.



**Fig. S6.** Transmittance spectra of ETPTA.



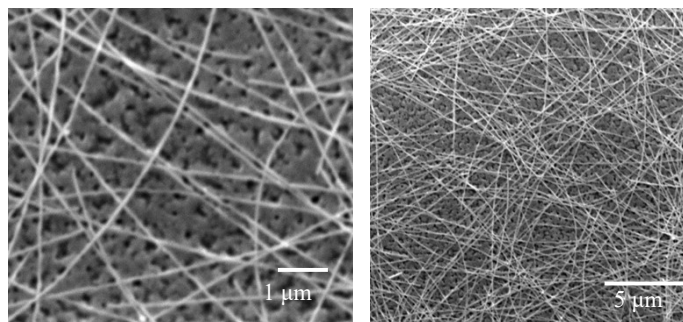
**Fig. S7.** Transmittance spectra of EC@ETPTA films with different ETPTA contents.



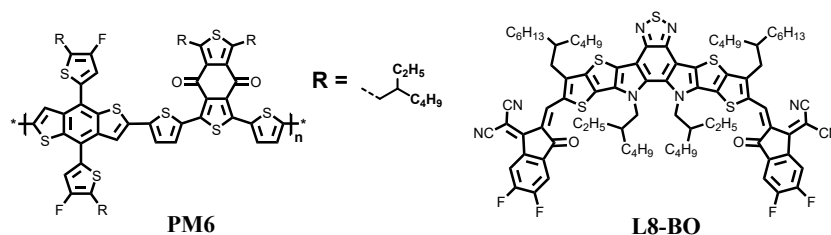
**Fig. S8.** The thickness of EC@ETPTA film was measured by a profiler.



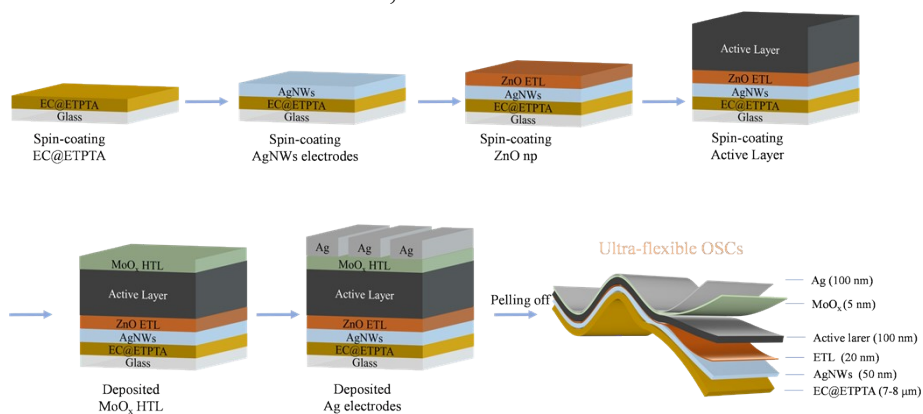
**Fig. S9.** Authentic pictures of EC@ETPTA (23×13 cm).



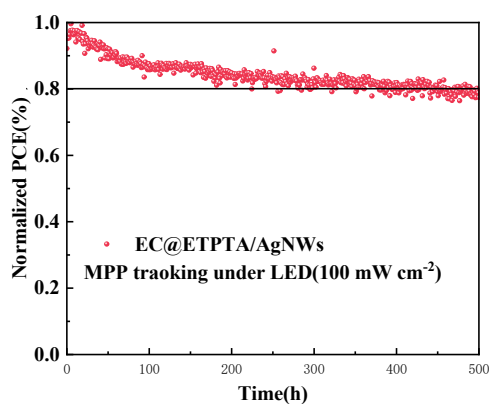
**Fig. S10.** SEM image of EC@ETPTA/AgNWs film.



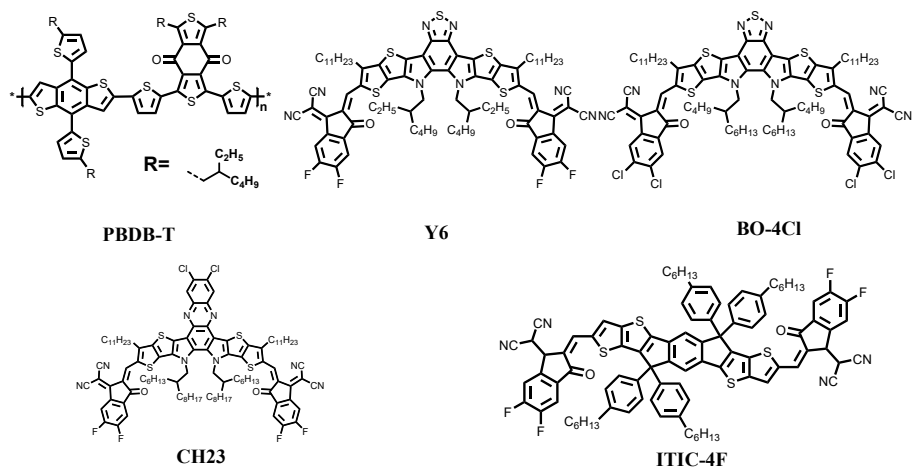
**Fig. S11.** Chemical structure of PM6, L8-BO.



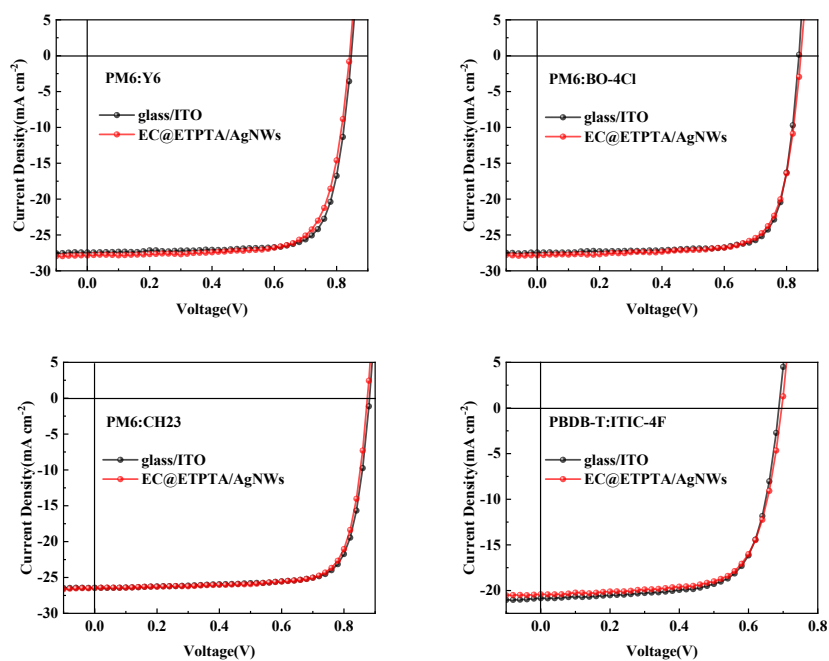
**Fig. S12.** The schematic diagram of the detailed preparation process of ultra-flexible OSCs.



**Fig. S13.** illumination stability at maximum power point (MPP) tracking of the flexible devices based on EC@ETPTA/AgNWs.

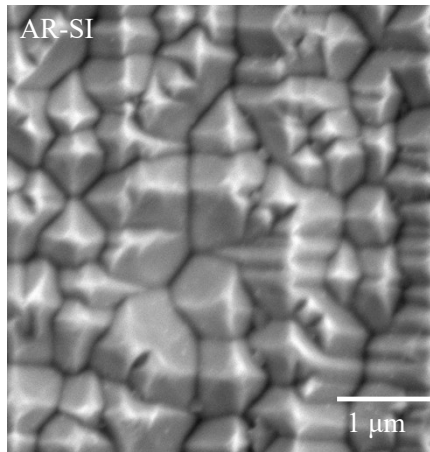


**Fig. S14.** Chemical structure of PBDB-T, Y6, BO-4Cl, CH23 and ITIC-4F.

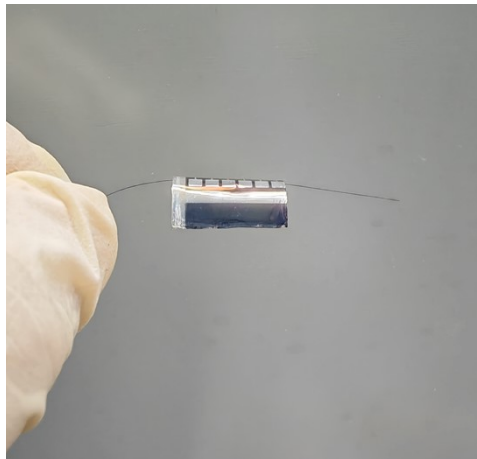


**Fig. S15.** J-V curves of OSCs based on EC@ETPTA/AgNWs and glass/ITO electrodes with different active layers.





**Fig. S16.** SEM image of a silicon wafer with AR structure (AR-Si).



**Fig. S17.** The display of an ultra-flexible OSCs device on a single human hair.



**Fig. S18.** Photograph of the free-standing OPVs attached to a finger.

#### 4. Supplementary Tables

**Table S1.** Properties of different electrode.

Electrode	T(%) @550 nm	Rsh ( $\Omega/\square$ )	FoM
Glass/ITO	89.56	12.45	267.12
EC@PEGDMA/AgNWs	88.92	21.04	148.14
PEN/ITO	83.52	16.48	121.39
PET/ITO	74.20	12.67	92.46

**Table S2.** Photovoltaic parameters of recently reported flexible OSCs

Device structure	$V_{oc}$ [V]	$J_{sc}$ [mA cm <sup>-2</sup> ]	FF [%]	PCE [%]	Refs
PPZA/ZnO/PM6: N3: PC <sub>71</sub> BM/MoO <sub>3</sub> /Ag	0.840	25.00	76.50	16.10	9
PET/AgNWs/ZnO: CsCO <sub>3</sub> /D18: Y6: PCB <sub>71</sub> M/MoO <sub>3</sub> /Ag	0.862	26.44	77.43	17.64	10
Em-AgNW FTE/ZnO/ PM6: L8-BO/MoO <sub>3</sub> /Ag	0.834	24.26	76.34	15.41	11
PET/Ag grids/D-PH1000/ PEDOT: PSS/D18: N3: QX- α/PDINN/Ag	0.856	27.21	77.30	18.01	12
PDMS/AgNWs/ZnO: CsCO <sub>3</sub> /D18: Y6: PCB <sub>71</sub> M/MoO <sub>3</sub> /Ag	0.860	26.94	16.48	17.72	13
Em-Ag/AgNWs:AZO-SG/PBDB-T-2F: Y6/MoO <sub>3</sub> /Al	0.832	25.05	72.97	15.21	14
PET/AgNWs@SnO <sub>x</sub> /ZnO/PM6: L8-BO/MoO <sub>3</sub> /Ag	0.860	25.5	75.80	16.60	15
PET/AgNW:PDA: AgNP /AZO/PBDB-T-2F: BTP- ec9:PCB <sub>71</sub> M/MoO <sub>3</sub> /Ag	0.830	27.44	74.96	17.07	16
AgNWs@CPI/ZnO/PM6: BTP-4Cl/MoO <sub>3</sub> /Ag	0.780	24.77	74.35	14.37	17
PET/Em-Ag/AgNWs/AZO/PM6: BTP-eC9: PC71BM/MoO <sub>3</sub> /Ag	0.835	27.37	76.90	17.52	18
FlexAgNEs/ZnO NPs/PFN-Br/PM6: Y6/MoO <sub>3</sub> /Ag	0.829	25.43	74.50	15.71	3
EC/PI/AgNWs/ZnO NPs/NMAO/PM6: L8-BO/MoO <sub>3</sub> /Ag	0.875	26.38	78.26	18.05	4
AR-EC@ETPTA/AgNWs/ZnO NPs/NMAO/PM6: L8- BO/MoO <sub>3</sub> /Ag	0.876	27.67	77.13	18.71	This work

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